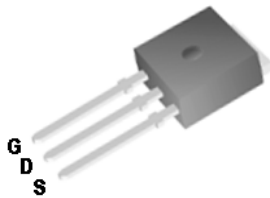


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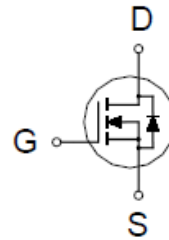
N-Channel Enhancement Mode MOSFET

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
650V	14Ω @ $V_{GS} = 10V$	1A



TO-251



ABSOLUTE MAXIMUM RATINGS ($T_A = 25\text{ °C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		V_{DS}	650	V
Gate-Source Voltage		V_{GS}	±30	
Continuous Drain Current ²	$T_C = 25\text{ °C}$	I_D	1	A
	$T_C = 100\text{ °C}$		0.6	
Pulsed Drain Current ^{1, 2}		I_{DM}	3	
Avalanche Current ³		I_{AS}	1.1	
Avalanche Energy ³	L = 10mH	E_{AS}	5.8	mJ
Power Dissipation ^A	$T_C = 25\text{ °C}$	P_D	27.6	W
	$T_C = 100\text{ °C}$		11	
Operating Junction & Storage Temperature Range		T_J, T_{STG}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		4.53	°C / W
Junction-to-Ambient	$R_{\theta JA}$		110	

¹Pulse width limited by maximum junction temperature.

²Limited only by maximum temperature allowed.

³ $V_{DD} = 50V$, Starting $T_J = 25\text{ °C}$

P0165AI

N-Channel Enhancement Mode MOSFET

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	650			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	2.5	3.6	4.5	V
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 30V$			± 250	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 650V, V_{GS} = 0V, T_C = 25^\circ C$			1	μA
		$V_{DS} = 520V, V_{GS} = 0V, T_C = 100^\circ C$			10	
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 0.5A$		9.7	14	Ω
Forward Transconductance ¹	g_{fs}	$V_{DS} = 10V, I_D = 0.5A$		1		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$		168		pF
Output Capacitance	C_{oss}			58		
Reverse Transfer Capacitance	C_{rss}			3		
Total Gate Charge ²	Q_g	$V_{DD} = 480V, I_D = 1A, V_{GS} = 10V$		5		nC
Gate-Source Charge ²	Q_{gs}			3.5		
Gate-Drain Charge ²	Q_{gd}			0.7		
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DD} = 300V, I_D = 1A, R_G = 25\Omega$		12		nS
Rise Time ²	t_r			40		
Turn-Off Delay Time ²	$t_{d(off)}$			20		
Fall Time ²	t_f			30		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current ³	I_S				1	A
Forward Voltage ¹	V_{SD}	$I_F = 1A, V_{GS} = 0V$			1.4	V
Reverse Recovery Time	t_{rr}	$I_F = 1A, di_F/dt = 100A / \mu S, V_{GS} = 0V$		160		nS
Reverse Recovery Charge	Q_{rr}			0.45		nC

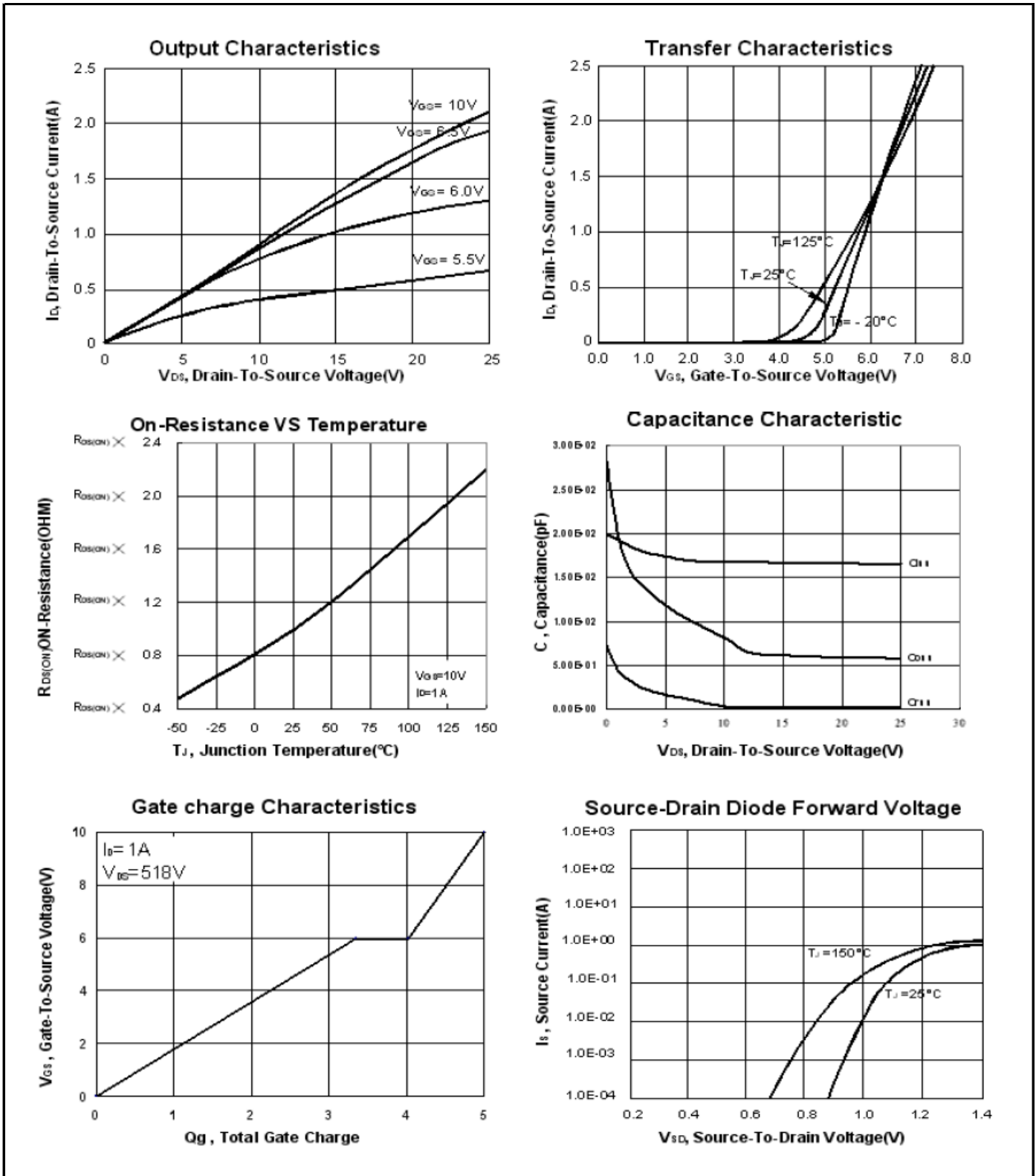
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

³Pulse width limited by maximum junction temperature.

P0165AI

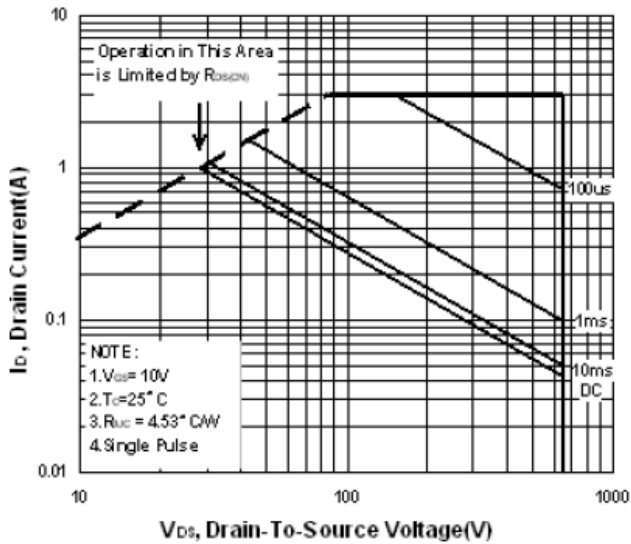
N-Channel Enhancement Mode MOSFET



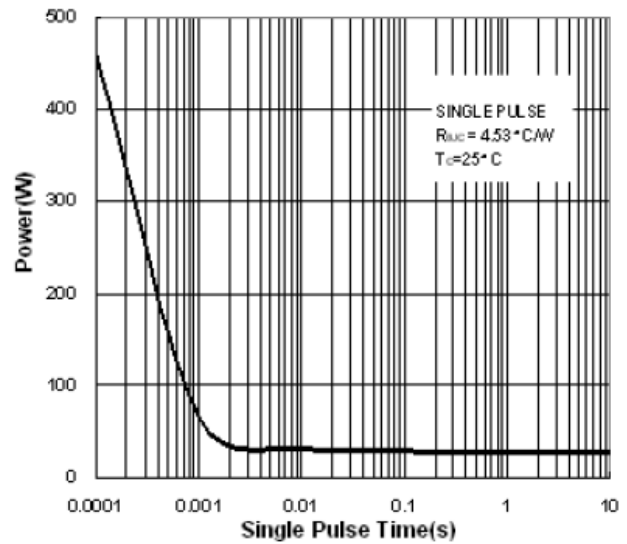
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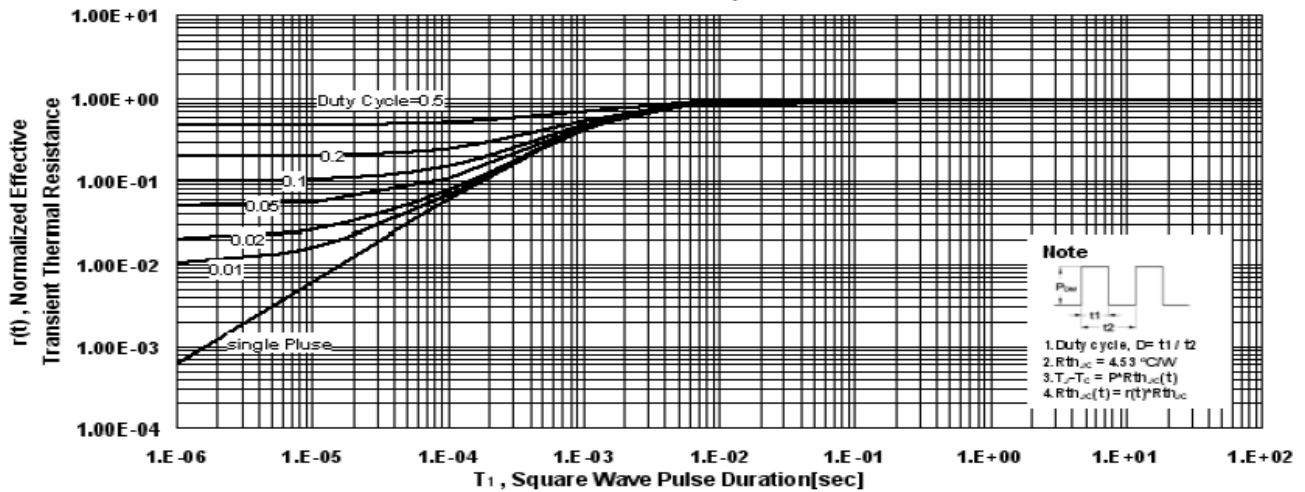
Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve



P0165AI

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Package Dimension

TO-251 MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	14	15	17.14	H	0.89		1.7
B	2.1	2.3	2.5	I	6.3		6.8
C	0.4	0.5	0.6	J	4.8		5.5
D	0.35	0.5	0.65	K	0.5	0.84	1.14
E	0.9	1.1	1.5	L	0.4	0.76	0.912
F	7		9.65	M		2.3	
G	5.3		6.22	N	1.4	2.16	2.23

